

# FORMATION OF HIGH-ASPECT RATIO SILICON NANOPILLARS USING DEEP REACTIVE ION ETCHING

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Formation of high-aspect ratio (height/diameter) nanopillars in monocrystalline silicon (known also as “black silicon”) attracts much attention due to numerous possible applications in, solar cells<sup>1</sup>, chemical analysis<sup>2</sup> and mechanical assembling<sup>3</sup>. Various methods of nanosilicon structures have been reported, including chemical wet etching<sup>2</sup> and deep reactive ion etching (DRIE)<sup>4</sup>. This paper presents a method for black-silicon formation by a Bosch process using an inductively coupled plasma (ICP) source and electroless deposited Ni-P films as a hard mask material.

Silicon wafers were processed using the following sequence: (1) BHF dip; (2) Palladium thin film electroless deposition; (3) Nickel-Phosphorus electroless deposition solution (about 1 μm thick layer of Ni-P hard mask for etching is deposited), 4) photolithography for sample surface patterning, and (5) Nickel-Phosphorus etching for pattern transfer. After these steps, the silicon wafers were etched by a Bosch process in an ICP plasma source using alternating etching/polymerizing (Ar+SF<sub>6</sub> /Ar+C<sub>4</sub>F<sub>8</sub>) gas mixtures. Plasma process parameters: ICP power and bias power (both 13.56 MHz) of 500 and 100 W, respectively, pressure of 50 mTorr, sample holder temperature of 20° C, mean etch rates up to 1 μm/min. As a result of etching, formation of very dense arrays of vertical silicon pillars in the Si areas not protected by Ni-P hard mask can be observed, see Fig. 1. The pillar diameters vary in the range of 100-300 nm, their aspect ratio can be as high as 100:1 and mean distance between pillars is 300-800 nm. Special experiments were performed to prove that the origin of pillars is micromasking due to re-deposition of Ni from the hard Ni-P mask. Currently, experiments are in course to get better control over the size distribution of pillars, looking for applications in photonics, in particular for solar cells.

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1 K. Nishioka et al., *Solar Energy Materials & Solar Cells* 92 (2008).

2 L. Sainiemi et al., *Nanotechnology* 18 (2007).

3 M. Stubenrauch *et al.*, *J. of Micromech. Microeng.* 16 (2006).

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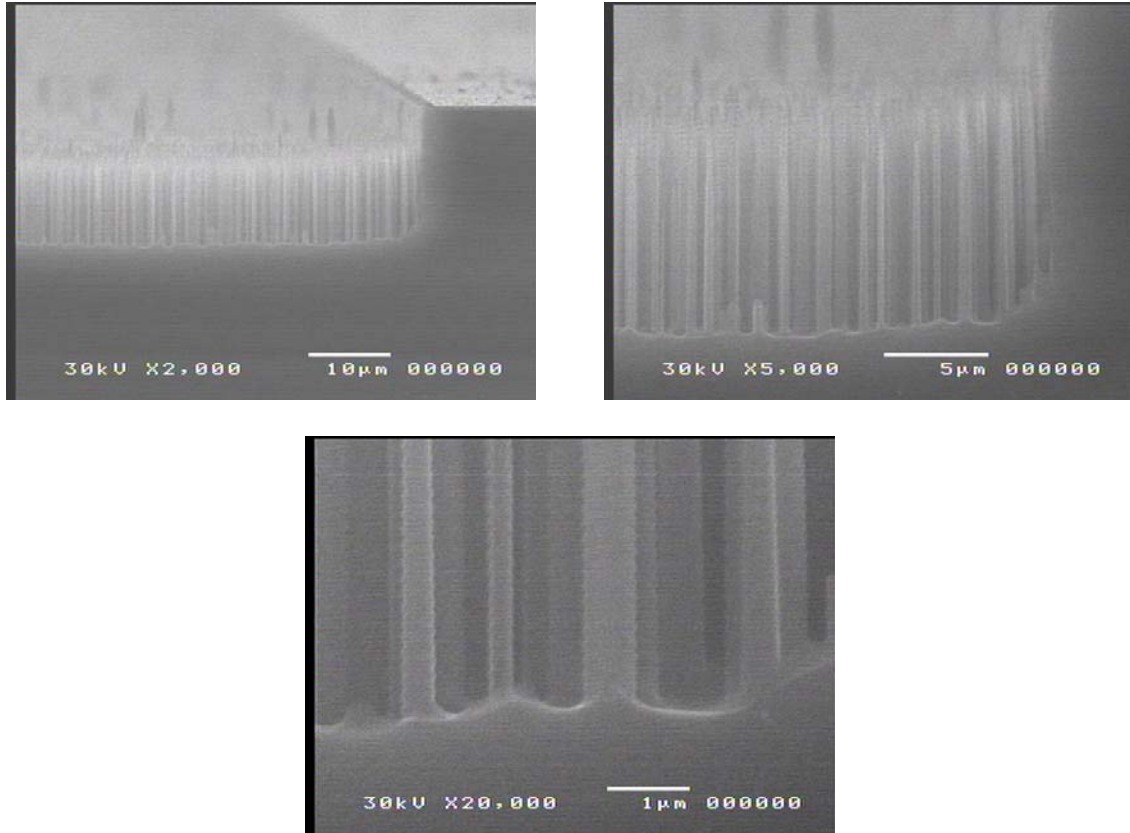


figure 1 – SEM images of silicon pillars forming the black-silicon.